

FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE										ATTY. DOCKET NO. S98-157/US		SERIAL NO. 09/993,338			
<b>LIST OF PRIOR ART CITED BY APPLICANT</b> (Use several sheets if necessary)										APPLICANT Scott R. Manalis et al.		FILING DATE 11/13/01		GROUP 2816	
<b>U.S. PATENT DOCUMENTS</b>															
EXAMINER INITIAL		DOCUMENT NUMBER							DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE		
<i>DR</i>	A	6	2	8	0	9	3	9	8/28/01	Allen	435	6	9/1/98		
<i>DR</i>	B	6	2	3	8	8	7	1	5/29/01	Koster	435	6	5/8/00		
<b>FOREIGN PATENT DOCUMENTS</b>															
		DOCUMENT NUMBER							ISSUE DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION		
													YES	NO	
	I														
	J														
	K														
<b>OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)</b>															
<i>DR</i>	L	Schafer et al. (1991); "Transcription of single molecules of RNA polymerase observed by light microscopy;" NATURE 352, PAGE 444													
<i>DR</i>	M	Yin et al. (1995); "Transcription against an applied force;" SCIENCE 270, PAGE 1653													
<i>DR</i>	N	K. K. Likharev; "Single-electron devices and their applications;" PROC. OF THE IEEE VOL. 87 NO. 4, APRIL 1999, PAGE 606													
<i>DR</i>	O	Yoo et al. (1997); "Scanning single electron transistor microscopy imaging individual charges;" SCIENCE 276, PAGE 579													
<i>DR</i>	P	Schoelkopf et al. (1998); "The radio-frequency single electron transistor: a fast and ultrasensitive electrometer;" SCIENCE 280, PAGE 1238													
<i>DR</i>	Q	Kazuhiko Matsumoto et al.; "Application of scanning tunneling microscopy nanofabrication process to single electron transistor;" J. VAC. SCI. TECHNOL. B14(2), MAR/APR 1996, PAGE 1331													
<i>DR</i>	R	Michel H. Devoret et al.; "Single-electron transfer in metallic nanostructures;" NATURE, VOL 360, 10 DECEMBER 1992													
EXAMINER <i>David Ruff</i>										DATE CONSIDERED 11/13/03					
* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.															